



Report No .:

EMC 1809099

File reference No.: 2018-10-10

Applicant:

Product:

Charging Cable

Brand Name:

N/A

Model No .:

MC17

Test Standards:

EN 55032:2015

EN61000-3-2:2014

EN 55024: 2010+A1:2015

EN 61000-3-3: 2013

Test result:

The EMC testing has been performed on the submitted

samples and found in compliance with council EMC Directive

2014/30/EU.

Approved B

Terry Tang Manager

Dated:

October 10, 2018

Results appearing herein relate only to the sample tested The technical reports is issued errors and omissions exempt and is subject to withdrawal at

SHENZHEN TIMEWAY TESTING LABORATORIES.

Zone C, 1st Floor, Block B, Jun Xiang Da Building, Zhongshan Park Road West, Tong Le Village, Nanshan District, Shenzhen, China

Tel (755) 83448688

Fax (755) 83442996

Email: info@timeway-lab.com

Date: 2018-10-10



Special Statement:

The testing quality ability of our laboratory meet with "Quality Law of People's Republic of China" Clause 19.

Page 2 of 42

The testing quality system of our laboratory meets with ISO/IEC-17025 requirements, which is approved by CNAS. This approval result is accepted by MRA of APLAC.

Our test facility is recognized, certified, or accredited by the following organizations:

CNAS-LAB Code: L2292

The EMC Laboratory has been assessed and in compliance with CNAS-CL01 accreditation criteria for testing Laboratories (identical to ISO/IEC 17025:2005 General Requirements) for the Competence of testing Laboratories.

Date: 2018-10-10



Page 3 of 42

TABLE OF CONTENT

1.0	Ger	neral Details	5
	1.1	Test Lab Details	5
	1.2	Applicant Details	5
	1.3	Description of EUT.	5
	1.4	Submitted Sample(s)	5
	1.5	Test Duration	5
	1.6	Additional information of EUT	<i>6</i>
	1.7	Test Engineer	6
2.0	List	t of Measurement Equipment	7
	2.1	Conducted Emission Test.	7
	2.2	Radiated Disturbance Test	7
	2.3	Harmonic & Flicker Test	7
	2.4	ESD Test	7
	2.5	RF field Strength Susceptibility	8
	2.6	Electrical Fast Transient/Burst (EFT/B) Immunity test	8
	2.7	Surge Test	8
	2.8	Conducted Immunity Test	8
	2.9	Power-frequency Magnetic Field	8
	2.10	Voltage Dips/Interruption Immunity Test	9
3.0	Tec	hnical Details	10
	3.1	Investigations Requested	10
	3.2	Test Standards	10
	3.3	Performance Criteria	10
	3.4	Test standards and Results Summary Tables	11
4.0	Ele	ctromagnetic Interference Test results	12
	4.1	Power line Conducted Emission Test	12
	4.2	Telecommunication ports Conducted Emission Test	15
	4.3	Radiated Disturbance Test	18
	4.4	Harmonic Current Emission Test.	21
	4.5	Voltage Fluctuations &Flicker Test	23
5.0	Imi	nunity Test	25
	5.1	Electrostatic Discharge	25
	5.2	RF field strength susceptibility (80MHz 1000MHz)	27
	5.3	Electrical Fast Transient/Burst (EFT/B) immunity test	29
	5.4	Surge test	31
	5.5	Conducted Immunity test	33
	5.6	Power-Frequency magnetic field test	35

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

Date: 2018-10-10



Page 4 of 42

	5.7	Voltage Dips/Interruptions immunity test	37
		ıct Labelling	
	6.1	CE Mark label specification	39
	6.2	Mark Location: Rear enclosure	39
7.0	Pho	oto of testing	40

Date: 2018-10-10



Page 5 of 42

1.0 General Details

1.1 Test Lab Details

SHENZHEN TIMEWAY TESTING LABORATORIES.

Zone C, 1st Floor, Block B, Jun Xiang Da Building, Zhongshan Park Road West, Tong Le Village, Nanshan District, Shenzhen, China

Tel(086) 755-83448688 Fax (086) 755-83442996

Test Location

All tests were performed at:

SHENZHEN TIMEWAY TESTING LABORATORIES.

Zone C, 1st Floor, Block B, Jun Xiang Da Building, Zhongshan Park Road West, Tong Le Village, Nanshan District, Shenzhen, China

Tel(086) 755-83448688 Fax (086) 755-83442996

No tests were sub-contracted.

	4 1' T	• •
1.2	Annlicant Data	ıla
1.4	Applicant Deta	шэ

Applicant:

Address:

Telephone:

Fax:

Manufacturer:

Address:

Telephone:

Fax:

1.3 Description of EUT

Product: Charging Cable

Brand Name: N/A
Model Number: MC17
Adding Model Number: N/A

Rating: Input: --

Remark: --

1.4 Submitted Sample(s)

1 Sample

1.5 Test Duration

Date of Receipt of Test Item: September 19, 2018 Date of Test: September 19, 2018~ October 10, 2018

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

THIS DOCUMENT WAS REDACTED WITH THE PRODUCTIP REDACTION TOOL ON 2018-10-12. AT THE TIME OF GENERATING THE DOCUMENT THE ORIGINAL DOCUMENT WAS REDACTED WITH THE PRODUCTIP REDACTION TOOL ON 2018-10-12. AT THE TIME OF GENERATING THE DOCUMENT THE ORIGINAL DOCUMENT WAS REDACTED WITH THE PRODUCTIP REDACTION TOOL ON 2018-10-12. AT THE TIME OF GENERATING THE DOCUMENT THE ORIGINAL DOCUMENT WAS REDACTED WITH THE PRODUCTIP REDACTION TOOL ON 2018-10-12. AT THE TIME OF GENERATING THE DOCUMENT THE ORIGINAL DOCUMENT WAS REDACTED WITH THE PRODUCTIP REDACTION TOOL ON 2018-10-12. AT THE TIME OF GENERATING THE DOCUMENT THE ORIGINAL DOCUMENT WAS AVAILABLE ALSO. THE ORIGINAL CAN ONLY BE MADE AVAILABLE BY THE DOCUMENT WAS REPACTED WITH THE PROPULLING THE DOCUMENT WAS AVAILABLE BY THE BY THE DOCUMENT WAS AVAILABLE BY THE BY THE DOCUMENT WAS AVAILABLE BY THE BY TH

Report No.: EMC1809099

Date: 2018-10-10



Page 6 of 42

1.6	Additional	information	of FIIT
1.0	Additional	IIIIOIIIIalioii	ULLUI

110 11011111111111111111111111111111111		
	Submitted	Not Available
User Manual	\boxtimes	
Part List		
Circuit Diagram	\boxtimes	
Printed circuit board[PCB] Layout	\boxtimes	
Block Diagram		
1.7 Test Engineer	SESTING LA	To be a second
The sample(s) tested by Print Na	Leo Lau/Engin	eer
	ERTIFICAT	0

This test report is not valid without personnel's signatures of SHENZHEN TIMEWAY TESTING LABORATORIES

Date: 2018-10-10



Page 7 of 42

2.0 List of Measurement Equipment

2.1 Conducted Emission Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
EMI Test Receiver	ESH3	860905/006	RS	2018.06.11	1Year
Spectrum Analyzer	ESA-L1500A	US37451154	HP	2018.06.11	1Year
PULSE LIMITER	ESH3-Z2	100281	RS	2018.06.11	1Year
LISN	ESH3-Z5	100294	RS	2018.06.11	1Year
LISN	ESH3-Z5	100253	RS	2018.06.11	1Year

2.2 Radiated Disturbance Test

				Calibration	Calibration
Name	Model No	Serial No.	Manufacturer	Date	Cycle
EMI Test Receiver	ESVD	100008	RS	2018.06.11	1Year
Coaxial Switch	MP59B	M70585	ANRITSU	N/A	N/A
Spectrum Analyzer	8595E	3441A00893	HP	2018.06.11	1Year
Amplifier	8447D	2727A05017	HP	2018.06.11	1Year
Bilog Antenna	VULB9163	9163/340	Schwarebeck	2018.06.11	1Year

2.3 Harmonic & Flicker Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Harmonics Flicker Test System	PACS-1	72305	CI	2018.06.11	1Year
5K VA AC Power Source	5001iX	56060	CI	2018.06.11	N/A

2.4 ESD Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
ESD Simulator	DITO	0404-24	EM TEST	2018.06.11	1Year

Date: 2018-10-10



Page 8 of 42

2.5 RF field Strength Susceptibility

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Signal Generator	SMT03	100059	RS	2018.06.11	1Year
Power Meter	NRVS		RS	2018.06.11	1Year
Voltage Probe	URV5-Z2	100012	RS	2018.06.11	1Year
Voltage Probe	URV5-Z2	100013	RS	2018.06.11	1Year
Power Amplifier	150W1000	300999	AR	2018.06.11	1Year
Power Amplifier	25S1G4AM1	305993	AR	2018.06.11	1Year
Field Probe	CBL6111C	2576	Holaday	2018.06.11	1Year
Bilog Antenna	MCDC		Chase	2018.06.11	1Year

Electrical Fast Transient/Burst (EFT/B) Immunity test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
EFT Generator	UCS 500 M4	0304-42	EM TEST	2018.06.11	1Year
Power Source	MV2616	0104-14	EM TEST	2018.06.11	1Year

2.7 Surge Test

					Calibration
Name	Model No.	Serial No.	Manufacturer	Calibration Date	Cycle
Ultra Compact	UCS 500				
Simulator	M4	0304-42	EM TEST	2018.06.11	1Year
Power Source	MV2616	0104-14	EM TEST	2018.06.11	1Year

2.8 Conducted Immunity Test

					Calibration
Name	Model No.	Serial No.	Manufacturer	Calibration Date	Cycle
Continuous					
Wave Simulator	CWS 500C	0407-05	EM TEST	2018.06.11	1 Year

Power-frequency Magnetic Field

					Calibration	Calibration
Name		Model No.	Serial No.	Manufacturer	Date	Cycle
Continuous	Wave					
Simulator		UCS 500 M4	0304-42	EM TEST	2018.06.11	1 Year
Power Se	ource					
Network		MV 2616	0104-14	EM TEST	2018.06.11	1 Year
Current Transfor	rmer	MC2630	-	EM TEST	2018.06.11	1 Year

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

In the event of the improper use of the report. The SHENZHEN TIMEWAY TESTING LABORATORIES. reserves the rights to withdraw it and to

adopt any other remedies which may be appropriate.

Date: 2018-10-10



Page 9 of 42

Magnetic Coil MS100 0304-42 EM TEST 2018.06.11 1 Yea	r
--	---

2.10 Voltage Dips/Interruption Immunity Test

		,			
				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Ultra Compact					
Simulator	UCS 500 M4	0304-42	EM TEST	2018.06.11	1Year
Power Source	MV2616	0104-14	EM TEST	2018.06.11	1Year

Date: 2018-10-10



Page 10 of 42

3.0 Technical Details

3.1 Investigations Requested

Perform Electromagnetic Interference [EMI] & Electromagnetic Susceptibility[EMS] tests for CE Marking

3.2 Test Standards

Test Standards							
EN 55032:2015	Electromagnetic compatibility of multi	imedia equipment - Emission Requirements					
EN61000-3-2:2014	Electromagnetic compatibility(EMC)- Part 3-2:Limits-Limits for harmonic current						
E1101000 5 2.2011	emissions(equipment input current ≤	16A per phase)					
	Electromagnetic compatibility (EMC	C)- Part 3-3:Limits-Limitation of voltage					
EN 61000-3-3:2013	changes, Voltage fluctuations and flick	er in public low-voltage supply systems. For					
EN 01000-3-3.2013	equipment with rated current $\leq 16A$	per phase and not subject to conditional					
	connection	connection					
EN	Information technology equipment — Immunity characteristics — Limits and						
55024:2010+A1:2015	methods of measurement						
	EN 61000-4-2:2009	Electrostatic discharge					
	EN 61000-4-3:2006	RF field strength susceptibility					
	EN 61000-4-4:2012	Electrical Fast transients					
	EN 61000-4-5:2014	Surge					
	EN 61000-4-6:2009	Conducted susceptibility					
	EN 61000-4-8:2010	Power-frequency Magnetic Field					
	EN 61000-4-11:2004	Dips/Voltage Interruption Variation					

3.3 Performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Date: 2018-10-10



Page 11 of 42

3.4 Test standards and Results Summary Tables

Test Condition	Test Requirement	Test Method	Test Result					
EMISSION Results Summary								
Conducted Emission on AC Mains,	EN 55032:2015	EN 55032:2015	Dogg					
150kHz to 30MHz			Pass					
Conducted Emission on at	EN 55032:2015	EN 55032:2015						
telecommunication ports,			N/A					
150KHz to 30MHz								
Radiated Emissions,	EN 55032:2015	EN 55032:2015	Pass					
30MHz to 1GHz			rass					
Harmonic Emissions on AC supply	EN61000-3-2:2014	EN61000-3-2:2014	N/A					
Voltage fluctuations on AC supply	EN 61000-3-3: 2013	EN 61000-3-3: 2013	N/A					
	IMMUNITY Results Sum	mary						
Electrostatic Discharge	EN 55024: 2010+A1:2015	EN 61000-4-2: 2009	Pass					
Electrical Fast transients	EN 55024: 2010+A1:2015	EN 61000-4-4: 2012	D					
/Burst Immunity			Pass					
RF field strength susceptibility	EN 55024: 2010+A1:2015	EN 61000-4-3: 2006	Pass					
Surge	EN 55024: 2010+A1:2015	EN 61000-4-5: 2014	Pass					
Conducted susceptibility	EN 55024: 2010+A1:2015	EN 61000-4-6: 2009	Pass					
Power-frequency Magnetic Field	EN 55024: 2010+A1:2015	EN61000-4-8: 2010	N/A					
Dips/Voltage Interruption Variation	EN 55024: 2010+A1:2015	EN 61000-4-11: 2004	Pass					

Note: N/A-Not applicable

Date: 2018-10-10

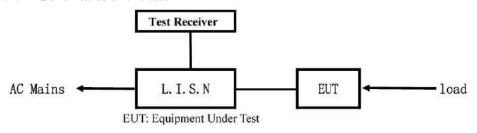


Page 12 of 42

4.0 Electromagnetic Interference Test results

4.1 Power line Conducted Emission Test

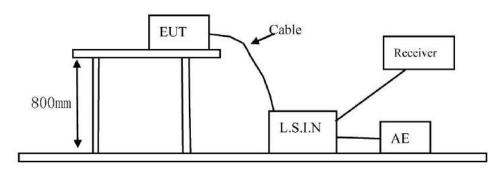
4.1.1 Schematics of the test



4.1.2 Test Method:

The test was performed in accordance with EN 55032:2015

Block diagram of Test setup



4.1.3 Power line conducted Emission Limit

	Limits dB(μ V)							
Frequency(MHz)	Class A E	quipment	Class B Equipment					
	Quasi-peak Level	Average Level	Quasi-peak Level	Average Level				
0.15 ~ 0.50	79.0	66.0	66.0~56.0*	56.0~46.0*				
0.50 ~ 5.00	73.0	60.0	56.0	46.0				
5.00 ~ 30.00	73.0	60.0	60.0	50.0				

Notes:

- 1. *decreasing linearly with logarithm of frequency.
- 2. The lower limit shall apply at the transition frequencies

4.1.4 Test Results

Limits for Conducted Emission test, Please refer to limit line (Quasi-peak)and Average in the following diagram labelled as (QP)&AV

Remark:

Calculated measurement uncertainty=3.6dB

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

Date: 2018-10-10



Page 13 of 42

A: Conducted Emission on Live Terminal (150kHz to 30MHz)

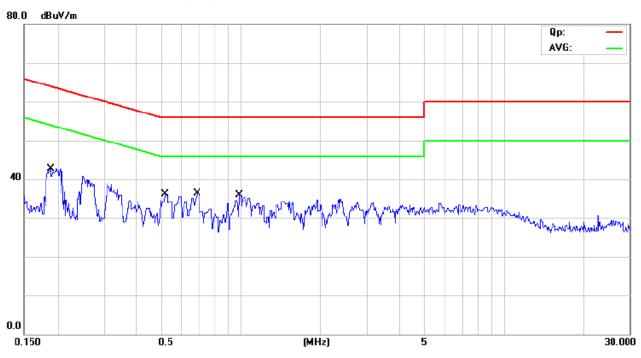
EUT Operating Environment

Temperature: 26°C Humidity: 65%RH Atmospheric Pressure: 101 kPa

EUT set Condition: Charging Equipment Level: Class B

Results: Pass

Please refer to following diagram for individual



No. Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over		
	MHz	dBuV/m	dB	dBuV/m	dBuV/m	dB	Detector	Comment
1	0.1887	28.60	9.89	38.49	64.09	-25.60	QP	
2	0.1887	11.40	9.89	21.29	54.09	-32.80	AVG	
3	0.5175	19.40	10.30	29.70	56.00	-26.30	QP	
4	0.5175	-6.10	10.30	4.20	46.00	-41.80	AVG	
5 *	0.6846	21.00	10.51	31.51	56.00	-24.49	QP	
6	0.6846	-1.90	10.51	8.61	46.00	-37.39	AVG	
7	0.6846	-2.00	10.51	8.51	46.00	-37.49	AVG	
8	0.9893	16.70	10.89	27.59	56.00	-28.41	QP	
9	0.9893	-6.50	10.89	4.39	46.00	-41.61	AVG	

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

Date: 2018-10-10



Page 14 of 42

B: Conducted Emission on Neutral Terminal (150kHz to 30MHz)

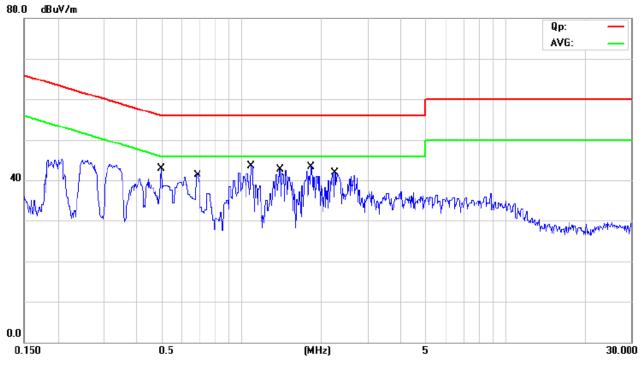
EUT Operating Environment

Temperature: 26°C Humidity: 65%RH Atmospheric Pressure: 101 kPa

EUT set Condition: Charging Equipment Level: Class B

Results: Pass

Please refer to following diagram for individual



			Reading	Correct	Measure-				
No.	Mk.	Freq.	Level	Factor	ment	Limit	Over		
		MHz	dBuV/m	dB	dBuV/m	dBuV/m	dB	Detector	Comment
1		0.4972	23.10	10.27	33.37	56.05	-22.68	QP	
2		0.4972	-6.90	10.27	3.37	46.05	-42.68	AVG	
3	*	0.6834	24.40	10.51	34.91	56.00	-21.09	QP	
4		0.6834	0.30	10.51	10.81	46.00	-35.19	AVG	
5		1.0914	21.70	10.90	32.60	56.00	-23.40	QP	
6		1.0914	-0.50	10.90	10.40	46.00	-35.60	AVG	
7		1.4013	20.80	10.89	31.69	56.00	-24.31	QP	
8		1.4013	-1.70	10.89	9.19	46.00	-36.81	AVG	
9		1.8300	19.60	10.88	30.48	56.00	-25.52	QP	
10		1.8300	0.90	10.88	11.78	46.00	-34.22	AVG	
11		2.2250	18.50	10.88	29.38	56.00	-26.62	QP	
12		2.2250	0.90	10.88	11.78	46.00	-34.22	AVG	

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

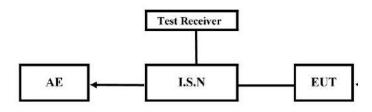
Date: 2018-10-10



Page 15 of 42

4.2 Telecommunication ports Conducted Emission Test

4.2.1 Schematics of the test

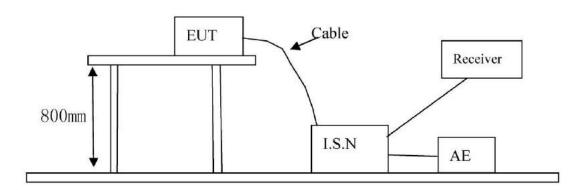


EUT: Equipment Under Test

4.2.2 Test Method:

The test was performed in accordance with EN 55032:2015

Block diagram of Test setup



4.2.3 Telecommunication ports conducted Emission Limit

	Class A Limits				Class B Limits			
Frequency(MHz)	Quasi-peak Level		Average Level		Quasi-peak Level		Average Level	
r requency(wiriz)	Vlotage dB(uV)	Current dB(uA)	Vlotage dB(uV)	Current dB(uA)	Vlotage dB(uV)	Current dB(uA)	Vlotage dB(uV)	Current dB(uA)
0.15 ~ 0.50	97 to 87	53 to43	84 to74	40 to 30	84 to 74	40 to30	74 to64	30 to 20
0.50 ~ 30.00	87	43	74	30	74	30	64	20

Notes:

- 1. *decreasing linearly with logarithm of frequency.
- 2. The tighter limit shall apply at the transition frequencies

4.2.4 Test Results

Limits for Conducted Emission test, Please refer to limit line (Quasi-peak)and Average in the following diagram labelled as (QP)&AV

Remark:

Calculated measurement uncertainty=1.9dB

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

Date: 2018-10-10



Page 16 of 42

A: Conducted Emission on Telecommunication port (150kHz to 30MHz)

EUT Operating Environment

Temperature: 25°C Humidity: 75 %RH Atmospheric Pressure: 101 kPa

EUT set Condition: Normal operation mode

Equipment Level: Class B

Results: N/A

Please refer to following diagram for individual

Frequency	Dort	Reading(dBμV)	Limit(dBµV)		
(MHz)	Port	Quasi-peak	Average	Quasi-peak	Average	
	LAN					
	LAN	-1		-		

Note: No such port, not applicable.

Date: 2018-10-10



Page 17 of 42

B: Conducted Emission on Telecommunication port (150kHz to 30MHz)

EUT Operating Environment

Temperature: 25°C Humidity: 75 %RH Atmospheric Pressure: 101 kPa

EUT set Condition: Normal operation mode

Equipment Level: ClassB

Results: N/A

Please refer to following diagram for individual

Frequency	Port	Reading(dBμA)	Limit(dBµA)		
(MHz)	Port	Quasi-peak	Average	Quasi-peak	Average	
	LAN					

Note: No such port, not applicable.

Date: 2018-10-10



Page 18 of 42

4.3 Radiated Disturbance Test

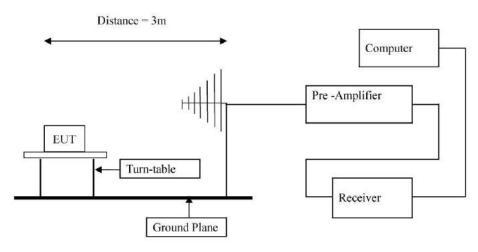
4.3.1 Schematics of the test



4.3.2 Test Method:

The test was performed in accordance with EN 55032:2015

Block diagram of Test setup



4.3.3 Radiated Disturbance Test Limit

Frequency Range (MHz)	Quasi-Peak limits (dB µ V/m)			
	Class A Limits	Class B Limits		
30-230	50.00	40.00		
230-1000	57.00	47.00		

Note: The lower limit shall apply at the transition frequencies

4.3.4 Test result

Limits for Radiated Disturbance test, Please refer to limit line (Quasi-peak) in the following diagram labelled as (QP)

Remark:

Calculated measurement uncertainty=4.7dB

Date: 2018-10-10



Page 19 of 42

Radiated Disturbance (30MHz----1000MHz) A:

Project Number: CASE1 2018-10-09_16.32.33 Test Time:

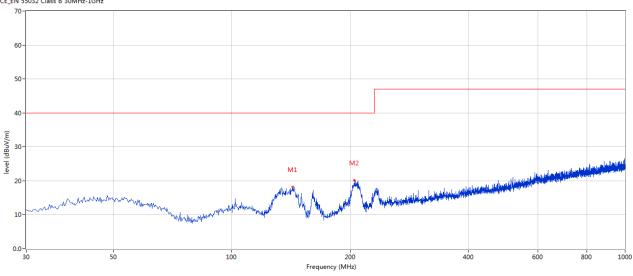
EUT Name: CHARGING CABLE Remark:

Manufacturer: N.A Model: MC17 Temp.(oC): 25 Hum.: 65%

Test Engineer: **CHARLES** Test Standard: EN 55032 Work Addition: **CAHRGING**

Load:

CE_EN 55032 Class B 30MHz-1GHz



No.	Frequen	Results	Factor	Limit	Over	Detector	Table (o)	Height	ANT	Verdict
	cy (MHz)	(dBuV/m	(dB)	(dBuV/m	Limit			(cm)		
))	(dB)					
1	142.734	18.22	-17.30	40.0	-21.78	Peak	360.00	200	Н	Pass
2	205.284	20.17	-13.61	40.0	-19.83	Peak	360.00	200	Н	Pass

Date: 2018-10-10



Page 20 of 42

B: Radiated Disturbance (30MHz----1000MHz)

Project Number: CASE1 Test Time: 2 0 1 8 - 1 0 - 0 9 _ 1 6 . 2 6 . 5 2

EUT Name: CHARGING CABLE Remark: Manufacturer: N.A Name:

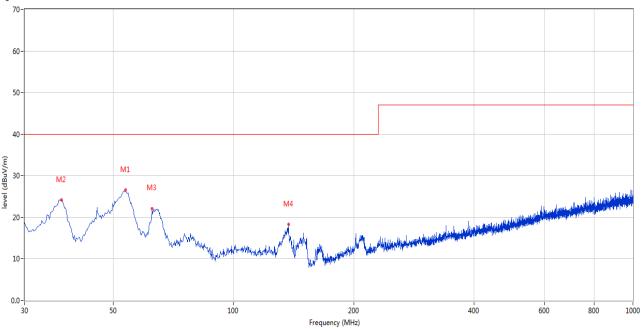
Model:MC17Project Template:Temp.(oC):25Manufacture:Hum.:65%Model Name:Test Engineer:CHARLESTempl.(oC):

Test Standard: EN 55032 Hum:

Work Addition: CHARGING Work Addition:

Load:

CE_EN 55032 Class B 30MHz-1GHz



No.	Frequency	Results	Factor (dB)	Limit	Over Limit	Detector	Table	Height	ANT	Verdict
	(MHz)	(dBuV/m)		(dBuV/m)	(dB)		(o)	(cm)		
1	53.759	26.60	-11.53	40.0	-13.40	Peak	226.00	100	V	Pass
2	37.031	24.21	-13.17	40.0	-15.79	Peak	43.00	100	V	Pass
3	62.487	22.12	-13.28	40.0	-17.88	Peak	306.00	200	V	Pass
4	137.401	18.35	-17.23	40.0	-21.65	Peak	360.00	100	V	Pass

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

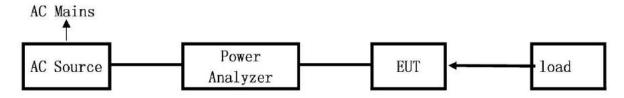
Date: 2018-10-10



Page 21 of 42

4.4 Harmonic Current Emission Test

4.4.1 Schematic of the test



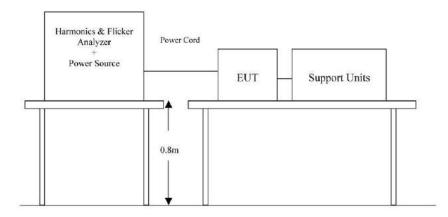
EUT: Equipment Under Test

4.4.2 Test Method:

The test was performed in accordance with EN61000-3-2:2014

*: The Level of the product is: CLASS D

Block diagram of Test setup



4.4.3 Limits of Harmonic Current Emission For Class A

Harmonic order	Maximum permissible harmonic current			
n	A			
Odd h	armonics			
3	2,30			
5	1,14			
7	0,77			
9	0,40			
11	0,33			
13	0,21			
$15 \leq n \leq 39$	0,15 15 n			
Even h	armonics			
2	1,08			
4	0,43			
6	0,30			
$8 \le n \le 40$	0,23 8 n			

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

Date: 2018-10-10



Page 22 of 42

4.4.4 Test Results

Please refer to the following pages

Harmonic Current Emission Test

EUT Operating Environment

Temperature: 25°C Humidity: 53%RH Atmospheric Pressure: 101 Kpa

EUT set Condition:

Results: N/A

Please refer to following diagram for individual

Harmonic results as a% of the limits

No	(Test	No	(Test	No	(Test	No	(Test
	result/Limit)%		result/Limit)%		result/Limit)%		result/Limit)%
1		11		21		31	
2		12		22		32	
3		13		23		33	
4		14		24		34	
5		15		25		35	
6		16		26		36	
7		17		27		37	
8		18		28		38	
9		19		29		39	
10		20		30		40	

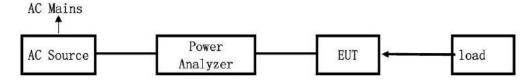
Date: 2018-10-10



Page 23 of 42

4.5 Voltage Fluctuations & Flicker Test

4.5.1 Schematic of the test

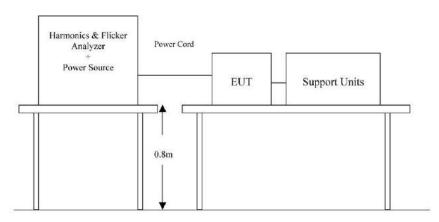


EUT: Equipment Under Test

4.5.2 Test Method:

The test was performed in accordance with EN 61000-3-3:2013

Block diagram of Test setup



Date: 2018-10-10



Page 24 of 42

4.5.3 Test Results

Result: N/A

Please refer to following diagram for individual

Maximum Occurring Levels:

Ut: 230.1 (EUT Test RMS Voltage)

Pst:	Limit=	1.0	(The Highest short Term Flicker Value)
Plt:	Limit=	0.65	(The Highest Long Term Flicker Value)
dt(%):	Limit=	3.3%	(The Highest instantaneous Voltage Change (10ms))
dc(%):	Limit=	3.3%	(The highest Relative steady state voltage change (1sec))
dmax:	Limit=	4%	(The highest Max Relative voltage change)
Tdt:	Limit=	500ms	(The Max Time(in milli-sec) that dt exceeds 3%)

Date: 2018-10-10

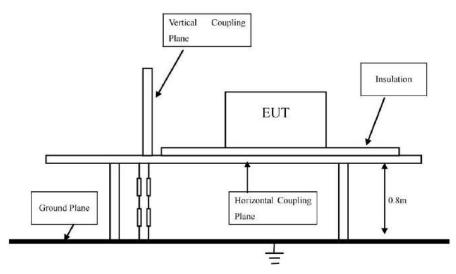


Page 25 of 42

5.0 Immunity Test

5.1 Electrostatic Discharge

5.1.1 Schematic of the test



5.1.2 Test method

The test was performed in accordance with EN 61000-4-2: 2009

5.1.3 Test severity

- ±4Kv for direct & in-direct Contact Discharge
- ± 8 Kv for air Discharge

Performance Criterion Require: **B** (Please see following table)

5.1.4 Susceptibility performance Criteria and Severity level

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
С	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Severity Level

Level	Test Voltage Direct & in-direct contact	Test Voltage Air
	Discharge (Kv)	discharge(Kv)
1	±2Kv	±2Kv
2	±4Kv	$\pm 4 \mathrm{Kv}$
3	±6Kv	$\pm 8 \mathrm{Kv}$
4	±8Kv	±15Kv

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

Date: 2018-10-10



Page 26 of 42

5.1.5 Test Result

EUT Operating Environment

Temperature: 25°C Humidity: 53%RH Atmospheric Pressure: 101 Kpa

Please refer to the following table for individual results.

Location	Discharge Method	Test Voltage	Results
НСР	In-Direct	$\pm 2kV, \pm 4kV$	Pass
VCP	In-Direct	$\pm 2kV, \pm 4kV$	Pass
Metal	Contact Discharge	$\pm 2kV, \pm 4kV$	Pass
Gap	Air Discharge	$\pm 2kV, \pm 4kV, \pm 8kV$	Pass
Enclosure	Air Discharge	$\pm 2kV, \pm 4kV, \pm 8kV$	Pass

Remark: Calculated measurement uncertainty= 0.2kV

Date: 2018-10-10



Page 27 of 42

5.2 RF field strength susceptibility (80MHz----- 1000MHz)

5.2.1 Schematics of the test



EUT: Equipment Under Test

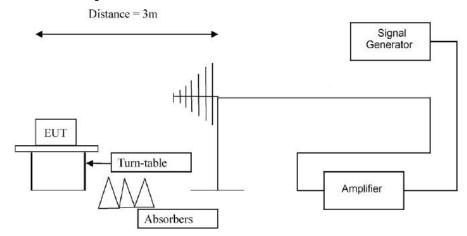
5.2.2 Test Method:

The test was performed in accordance with EN 61000-4-3:2006

Severity: Level 2 (3V/m) Modulation: 80% AM

Performance Criterion Require: A (Please see following table)

Block diagram of Test setup



5.2.3 Susceptibility performance Criteria and severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
С	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Severity Level

Level	Field Strength (V/m)
1	1
2	3
3	10

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

Date: 2018-10-10



Page 28 of 42

5.2.4 Test Result:

EUT Operating Environment

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to the following table for individual results.

Frequency	Face	Polarity	Level	Dwell	Sweep	Results
(MHz)			(V/m)	Time(s)	Rate (%)	
80-1000	0°	Horizontal	3	1	1	Pass
80-1000	90°	Horizontal	3	1	1	Pass
80-1000	180°	Horizontal	3	1	1	Pass
80-1000	270°	Horizontal	3	1	1	Pass
80-1000	0°	Vertical	3	1	1	Pass
80-1000	90°	Vertical	3	1	1	Pass
80-1000	180°	Vertical	3	1	1	Pass
80-1000	270°	Vertical	3	1	1	Pass

Remark: Calculated measurement uncertainty= 80MHz to 1000MHz (+3.7/-1.3) V/m

Date: 2018-10-10



Page 29 of 42

5.3 Electrical Fast Transient/Burst (EFT/B) immunity test

5.3.1 Schematics of the test



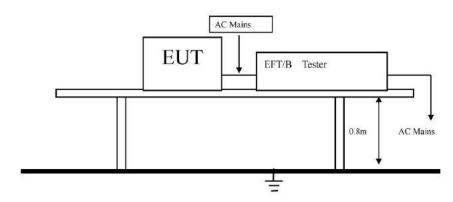
5.3.2 Test Method

The test was performed in accordance with EN 61000-4-4:2012

Severity: Level 2 (1kV)

Performance Criterion Require: B (Please see following table)

Block diagram of Test setup



5.3.3 Susceptibility performance Criteria and Severity Level

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Severity Level

	Open Circuit output Test Voltag	e ±10%
Level	On power Supply Lines	On I/O (Input/output)
		Signal data and control lines
1	0.5kV	0.5kV
2	1kV	1kV
3	2kV	2kV
4	4kV	4kV
X	Special	Special

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

Date: 2018-10-10



Page 30 of 42

5.3.4 Test Results

EUT Operating Environment

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to following page.

Inject location: AC mains

Inject Line	Voltage kV	Inject Times (s)	Method	Results
L	±1	120	Direct	Pass
N	±1	120	Direct	Pass
L-N	±1	120	Direct	Pass

Date: 2018-10-10



Page 31 of 42

5.4 Surge test

5.4.1 Schematics of the test



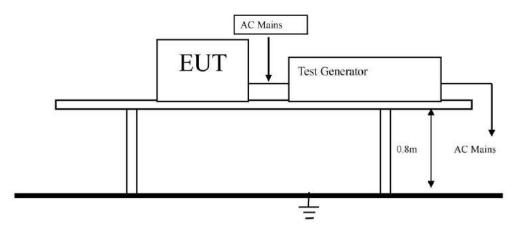
5.4.2 Test Method:

The test was performed in accordance with EN 61000-4-5:2014

Severity: Level 2 (Line to Neutral at 1kV)

Performance Criterion Require: B (Please see following table)

Block diagram of Test setup



5.4.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
С	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Date: 2018-10-10



Page 32 of 42

Severity Level

Severity Level	Open-Circuit Test Voltage		
	kV		
1	0.5		
2	1.0		
3	2.0		
4	4.0		
*	Special		

5.4.4 Test Results

EUT Operating Environment

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to following page.

Test location:

Location	Polarity	Phase	No of	Pulse	Results
		Angle	Pulse	Voltage(kV)	
	±	0	5	1.0	Pass
LN	<u>±</u>	90	5	1.0	Pass
L-N	<u>±</u>	180	5	1.0	Pass
	<u>±</u>	270	5	1.0	Pass

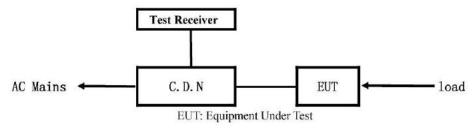
Date: 2018-10-10



Page 33 of 42

5.5 Conducted Immunity test

5.5.1 Schematics of the test



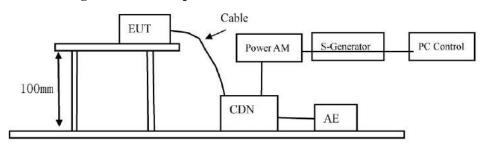
5.5.2 Test Method

The test was performed in accordance with EN 61000-4-6:2009

Severity: Level 2 (3 V rms),0.15MHz—80MHz

Performance Criterion Require: A (Please see following table)

Block diagram of Test setup



5.5.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
С	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Severity Level

Severity Level	Voltage Level (e.m.f) V
1	1
2	3
3	10
*	Special

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

Date: 2018-10-10



Page 34 of 42

5.5.4 Test Results:

EUT Operating Environment

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to the following page

	0, 0				
Frequency Range (MHz)	Injected Position	Strength	Criterion	Observation	Result
0.15 - 20	AC Line	3V (rms) Unmodulated	A	A	Pass
20 - 80	AC Line	3V (rms) Unmodulated	A	A	Pass

Date: 2018-10-10



Page 35 of 42

5.6 Power-Frequency magnetic field test

5.6.1 Schematics of the test



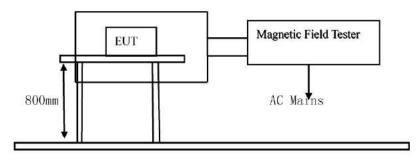
5.6.2 Test Method

The test was performed in accordance with EN 61000-4-8:2010

Severity: Level 1 (1A/m),

Performance Criterion Require: A (Please see following table)

Block diagram of Test setup



5.6.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
С	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Severity Level

Severity Level	Magnetic Field Strength A/m
1	1
2	3
3	10
4	30
5	100
*	Special

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

Date: 2018-10-10



Page 36 of 42

5.6.4 Test Results:

EUT Operating Environment

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to the following page

Test Level	Testing Duration	Coil Orientation	Criterion	Result			
1A/m	5 Mins	X	A	N/A			
1A/m	5 Mins	Y	A	N/A			
1A/m	5 Mins	Z	A	N/A			

Date: 2018-10-10



Page 37 of 42

5.7 Voltage Dips/Interruptions immunity test

5.7.1 Schematics of the test

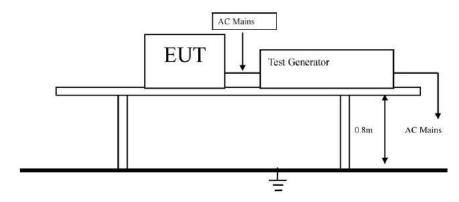


5.7.2 Test Method:

The test was performed in accordance with EN 61000-4-11:2004

Performance Criterion Require: C&B (Please see following table)

Block diagram of Test setup



5.7.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
С	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Date: 2018-10-10



Page 38 of 42

Severity Level

	Test Level %Ut	Reduction	Duration	Performance
Voltage			(Periods)	Criteria
Dip	<5	>95	0.5	В
	70	30	25	C
Walters	Test Level %Ut	Reduction	Duration	Performance
Voltage Interceptions			(Periods)	Criteria
	<5	>95	250	C

5.7.4 Test Result:

EUT Operating Environment

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to the following page

Voltage Dip:

Test Level	Reduction	Duration	Phase Angle	Meet	Result
% Ut		(periods)		Criterion	
0	100	0.5	0° -360°	A	Pass
70	30	25	0° - 360°	A	Pass

Voltage Interceptions:

Test Level % Ut	Reduction	Duration (periods)	Phase Angle	Meet Criterion	Result
0	100	250	0° - 360°	В	Pass

Date: 2018-10-10



Page 39 of 42

6.0 Product Labelling

6.1 CE Mark label specification

Text of the mark is black or white in color and is left justified. Labels are printed in indelible ink on permanent adhesive backing and shall be affixed at a conspicuous location on the EUT or silk-screened onto the EUT.



6.2 Mark Location: Rear enclosure

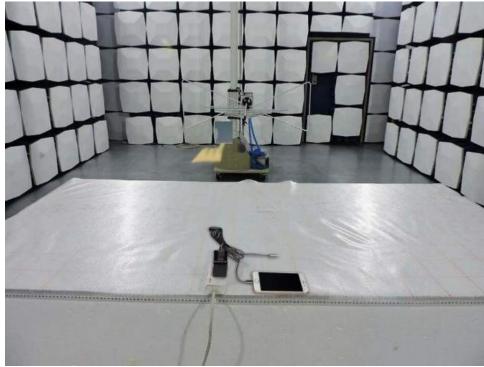
Date: 2018-10-10



Page 40 of 42

7.0 Photo of testing





The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

Date: 2018-10-10



Page 41 of 42

Photo for the EUT





The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

Date: 2018-10-10



Page 42 of 42

Photo for the EUT





-End of the report-

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.